# Effects of Platinum Doping on the Photoelectrochemical Properties of Fe<sub>2</sub>O<sub>3</sub> Electrodes

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The effects of platinum (Pt) doping on the structure and photoelectrochemical properties of  $Fe_2O_3$  electrodes have been investigated. The Pt-doped  $Fe_2O_3$  electrodes were prepared by sol-gel and spin coated on fluorine-tin-oxide coated glass substrate. Influences of dopant concentration on material properties and photoelectrochemical characteristics were examined. Results of XRD and XPS showed that  $\alpha$ -Fe<sub>2</sub>O<sub>3</sub> can be obtained using 500 °C annealing in air. The band gaps of the samples obtained from reflectance and transmittance spectra measurement were found to vary from 1.98 to 2.03 eV. The flat band potentials of the samples were obtained from the Mott-Schottky analysis and found to be in the range of -0.135 V to -0.6 V. The maximum photocurrent density of undoped and 0.1 at.% Pt-doped  $Fe_2O_3$  electrodes was 0.5 mA/cm<sup>2</sup> and 0.7 mA/cm<sup>2</sup> under a 300 W Xe lamp system, respectively. The good photoelectrochemical results of the Pt-doped  $Fe_2O_3$  electrode warrant further investigation for broader applications in the future.

Keywords: Fe<sub>2</sub>O<sub>3</sub>, Pt-doping, Sol-gel process, Photoelectrochemical method, thin films

## **1. INTRODUCTION**

Hydrogen is a promising energy carrier for the future [1]. It can be produced by many methods from a variety of sources. One promising method is the photoelectrochemical (PEC) splitting of water using solar irradiation [2-7]. The n-type titanium dioxide (TiO<sub>2</sub>) is a promising substrate for photogeneration of hydrogen from water, and many works have been done in modifying the microstructure of the material to increase the energy conversion efficiency [8]. Other semiconductors, such as Fe<sub>2</sub>O<sub>3</sub>, WO<sub>3</sub>, and ZnO, have also attracted much attention.

Hematite ( $\alpha$ -Fe<sub>2</sub>O<sub>3</sub>) has emerged as a promising photo-electrode material due to its significant light absorption, chemical stability in aqueous environments, and ample abundance. The energy band

gap of  $\alpha$ -Fe<sub>2</sub>O<sub>3</sub> is about 2.1 eV, enabling better utilization of the solar energy for water splitting than using TiO<sub>2</sub> electrodes. Good stability of the  $\alpha$ -Fe<sub>2</sub>O<sub>3</sub> electrode in alkaline solution was discussed by Kennedy and Frese [9]. Aroutiounian et al. [10-11] have reported the hopping mechanisms of various doping metals (Nb, Sn, Ta) with iron oxide powder in photoelectrochemical systems. The results indicated that photon-electron conversion efficiency of Nb-doped  $\alpha$ -Fe<sub>2</sub>O<sub>3</sub> thin films was 26 % under illumination conditions of simulated Air Mass (AM) 1.5 solar irradiation [12]. The photoelectrochemical properties of Cu and Zn doped  $\alpha$ -Fe<sub>2</sub>O<sub>3</sub> thin films was reported by Satsangi et al. [13]. They found that 1.5 at% Zn doped  $\alpha$ -Fe<sub>2</sub>O<sub>3</sub> exhibited the highest photocurrent density, 87.9  $\mu$ A/cm<sup>2</sup> at 0.6 V vs. SCE (pH=13). The photocurrent responses of Si-doped  $\alpha$ -Fe<sub>2</sub>O<sub>3</sub> at 0.5 V vs. Ag/AgCl (pH=13.6) in 1M NaOH was approximately 60  $\mu$ A/cm<sup>2</sup>.

Luo et al. [15] used WO<sub>3</sub>/Fe<sub>2</sub>O<sub>3</sub> composite thin film to enhance photocurrent density. They proposed that the photo-generated electrons could transfer more easily in WO<sub>3</sub>/Fe<sub>2</sub>O<sub>3</sub> than in WO<sub>3</sub> or Fe<sub>2</sub>O<sub>3</sub> alone because the conduction band of WO<sub>3</sub> is higher than that of Fe<sub>2</sub>O<sub>3</sub>. Later, Wang et al. [16] prepared SrTiO<sub>3</sub>/Fe<sub>2</sub>O<sub>3</sub> composite photoanode by spin-coating. They found that the photocurrent of the SrTiO<sub>3</sub>/ $\alpha$ -Fe<sub>2</sub>O<sub>3</sub> heterojunction were higher than that of the single SrTiO<sub>3</sub> or  $\alpha$ -Fe<sub>2</sub>O<sub>3</sub> film, particularly under visible light irradiation. Sartoretti et al. [17] prepared Ti-doped iron oxide thin film by spray pyrolysis. They found that doping Ti increases the conductivity and stability of iron oxide film. On the other hand, doping Ni or In reduces the photocurrent density.

In this study we investigate the effect of Pt doping on the structures and optical and PEC properties of  $\alpha$ -Fe<sub>2</sub>O<sub>3</sub> thin film photoanode.

#### 2. EXPERIMENTAL METHODS

## 2.1. Preparation of electrodes

Un-doped Fe<sub>2</sub>O<sub>3</sub> and Pt-doped Fe<sub>2</sub>O<sub>3</sub> were prepared by sol-gel spin-coating on fluorine doped tin oxide (FTO) glasses. The substrates were cleaned with alcohol, acetone, and isopropanol before each coating. The precursor of reaction solvent was FeCl<sub>3</sub>·6H<sub>2</sub>O (0.5 M), adjusted to a volume ratio of 36:1:1 mixture of (CH<sub>3</sub>)<sub>2</sub>CHOH, HOCH<sub>2</sub>CH<sub>2</sub>OH, and HCl. Platinum was added from different PtCl<sub>6</sub>H<sub>2</sub>·6H<sub>2</sub>O. The molar ratio of Pt to Fe was controlled at 0.1 %, 0.5%, 1.0%, and 1.5 %. Dust and other suspended impurities were removed from the solution by filtering through a 0.2 µm syringe filter. The spin speed was kept at 5000 rpm for 20 seconds. All films were heated in air at 250°C for evaporation of the solvent, and then heat treated at 500°C for 2 hours.

### 2.2. Characterization of electrodes

The morphology of samples was observed using field emission scanning electron microscope (FE-SEM, JEOL, JSM-7401F). The crystal structure of samples was measured using an X-ray

diffractometer (XRD, Shimadzu, XRD-6000 X) with CuK $\alpha$  ( $\lambda = 1.5418$  Å) radiation in the 2 $\theta$  range of 20-65°. The scan rate was 5 °/min.

The optical characteristic of samples was measured by UV-Vis spectrophotometer with an integrating sphere (JASCO, V-670) and resolution of 1 nm. After obtaining the transmittance, *T* and reflectance, *R* of the Fe<sub>2</sub>O<sub>3</sub> films, the absorption coefficient ( $\alpha$ ) can be calculated from [18]:

$$\alpha = \frac{1}{d} \left( \ln \frac{1 - R}{T} \right) \tag{1}$$

where d (nm) is the thickness of the film. The energy band gap,  $E_g$  can then be determined from the following equation [19]:

$$\alpha hv = A \left( hv - E_g \right)^n \tag{2}$$

where hv is the incident photo energy, A is a constant. n = 1/2 indicates direct allowed transition, and n = 2 indicates indirect allowed transition.

Mott-Schottky (M-S) measurements for the evaluation of the flat-band potentials of samples were performed using a potentiostat (Autolab, ECO CHEMIE, PGSTAT302) with a frequency response analyzer. The applied potentials were set in the range of -0.8 to + 0.2 V (versus Ag/AgCl reference electrode). The frequency of the Mott-Schottky plots was set at 1 kHz in this study. The flat-band potential ( $E_{fb}$ ) for Fe<sub>2</sub>O<sub>3</sub> thin films can be determined using [20]:

$$\frac{1}{C^2} = \left[\frac{2}{q\varepsilon\varepsilon_0 N_D}\right] \left[E - E_{fb} - \left(\frac{kT}{q}\right)\right]$$
(3)

where C, q,  $\varepsilon_0$ ,  $N_D$  and  $E_{fb}$  are capacitance, the electron charge, permittivity in vacuum, donor carrier density and flat-band potential of the semiconductor, respectively. The flat-band potentials of samples can be obtained from the intersection of the  $C^2$  vs. applied potential, E, plot.

Furthermore, the PEC performances of films were measured in a standard three-electrode system consisting of a Fe<sub>2</sub>O<sub>3</sub> sample as the working electrode, a Pt plate ( $\sim 1 \times 1 \text{ cm}^2$ ) as the counter electrode, Ag/AgCl as the reference electrode, and Na<sub>2</sub>S (0.35 M) and K<sub>2</sub>SO<sub>3</sub> (0.25 M) as the aqueous electrolyte (pH value = 13). The electrolyte was prepared using double deionized water and degassed by purging with nitrogen gas before each experiment. The photocurrent density of films, as a function of applied voltage, was varied from - 0.5 V to + 1.0 V vs. Ag/AgCl reference electrode (scan rate = 0.05 V/s) and using a 300 W solar simulator (Newport-Oriel Instruments, Model: 91160-1000) with AM 1.5 filter as a light source.

### **3. RESULTS AND DISCUSSION**

The crystal structures of the un-doped and Pt-doped  $(0.1 \circ 0.5 \circ 1.0 \circ 1.5 \text{ at\%})$  Fe<sub>2</sub>O<sub>3</sub> after solgel spin-coating and annealing are shown in Figure 1. The intensity of diffractive peak corresponding to  $\alpha$ -Fe<sub>2</sub>O<sub>3</sub> crystallinity increases with the content of Pt doped. The grain size can be obtained with the aid of Scherrer's equation

$$D = \frac{0.9\lambda}{\beta\cos\theta} \tag{4}$$

where D,  $\lambda$ ,  $\beta$  and  $\theta$  are the mean grain size, X-ray wavelength, the full width at half maximum (FWHM) of the diffraction peak, and the Bragg angle, respectively.



Figure 1. X-ray diffraction results of undoped and Pt-doped Fe<sub>2</sub>O<sub>3</sub> thin films.



Figure 2. XPS Fe 2p orbital spectra of Fe<sub>2</sub>O<sub>3</sub> thin films.



(b)

NCTU Sb:30 SEM SEI 10.0kV X100,000 V/D 3.0mm 100mm

(a)

(c)

Figure 3. FE-SEM images of Fe<sub>2</sub>O<sub>3</sub> thin films (a) undoped (b) 0.1 at % Pt doped and (c) 1.5 at % Pt doped.

From this equation, the grain size of the undoped sample calculated from the (110) peak was found to be 64 nm. The grain size decreases from 56, 52, 50, to 44nm as the amount of Pt doped increasing from 0.1, 0.5, 1.0, 1.5 at%. Figure 2 shows the XPS results of un-doped and Pt-doped Fe<sub>2</sub>O<sub>3</sub> thin films. The  $2p_{3/2}$  and  $2p_{1/2}$  signals were observed.

Table 1. Values	of physical	properties for	or Pt-doped	a-Fe <sub>2</sub> O <sub>3</sub> thin films	s.
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Atmosphere	Pt (at%)	Thickness (nm)	$E_g$ (eV)	$E_{fb}$ (V vs. Ag/AgCl)	Conduction type
Air	0 at%	228.4	2.03	-0.600	n
	0.1 at%	267.5	2.02	-0.321	n
	0.5 at%	201.5	2.00	-0.235	n
	1.0 at%	270.3	1.99	-0.155	n
	1.5 at%	167.9	1.98	-0.135	n

The fact that the satellite peak is closer to  $2p_{1/2}$  confirms the samples are pure iron oxide of alpha phase [21]. The small amount of Pt doping does not alter the chemical state of  $\alpha$ -Fe<sub>2</sub>O<sub>3</sub> thin film. The thickness of the samples was measured by  $\alpha$ -step and found to range from 168 to 268 nm as shown in Table 1. The FE-SEM images for the un-doped and Pt-doped  $\alpha$ -Fe<sub>2</sub>O<sub>3</sub> thin films are shown in Figure 3. They show worm-like grains.



Figure 4. Transmittance spectra of Fe<sub>2</sub>O<sub>3</sub> films.

Figure 4 shows transmittance spectrum measured at room temperature by ultraviolet-visible spectrometer. These films are highly transparent in the range from 580 nm to 700 nm. A similar result was also observed by Ismail et al [22]. The  $(ahv)^{1/2}$  vs. hv plot is shown in Figure 5. The band gap of the samples can be obtained from extrapolating the linear portions of the respective curve to  $(ahv)^{1/2} = 0$ . The band gap of the various Pt-doped Fe<sub>2</sub>O<sub>3</sub> films was found to be in the range of 1.98-2.03 eV. We observed that the band gap is slightly red-shifted by increasing Pt doping concentration. Figure 6 shows the Mott-Schottky plots for the samples. The flat band potentials were obtained by extrapolating the curves to the intercept with C<sup>-2</sup> = 0. The positive slope of the Mott-Schottky plots are in the range from -0.135 to -0.6 V vs. Ag/AgCl electrode, and increases with the amount of Pt doped. The flat band potential shifting toward positive is probably due to the electronic structure change with platinum doped in Fe<sub>2</sub>O<sub>3</sub> films. Values of band gaps and flat band potentials of the samples are also summarized in Table 1.



**Figure 5.** Plots of  $(\alpha hv)^{1/2}$  vs. hv of doped and undoped films.



Figure 6. Mott-Schottky plots of doped and undoped films in 0.5 M  $K_2SO_3$  + NaOH as the electrolyte (pH =13).

Figure 7 demonstrates photocurrent density as a function of applied potential (vs. Ag/AgCl) of the un-doped and Pt-doped Fe<sub>2</sub>O<sub>3</sub> samples in 0.5 M K<sub>2</sub>SO<sub>3</sub> + NaOH (pH = 13) electrolyte solution. It is interesting to note that the onset voltage of photocurrent of Fe<sub>2</sub>O<sub>3</sub> samples shifts toward more positive

with increasing concentration of Pt-doping, consistent with the Mott-Schottky measurement results. It can be seen that 0.1 at% Pt-doped  $Fe_2O_3$  exhibited the maximum photocurrent density value of 0.7 mA/cm<sup>2</sup>.



**Figure 7.** Photocurrent density - applied voltages plots of samples under 300 W solar simulators (AM 1.5G, 100 mW/cm<sup>2</sup>, 25°C).

Compared to the maximum photocurrent density of  $0.5 \text{ mA/cm}^2$  of the un-doped sample, the enhancement is about 40 %. The addition of Pt increases electronic conduction. Adding Pt also increases crystallinity of Fe<sub>2</sub>O<sub>3</sub> as evidenced by the intensity of the (110) peak in XRD results that helps charge carriers transfer more effectively. However, the photocurrent density decreases as the amount of Pt is further increased. As shown previously, the grain size decreases with increase Pt concentration. Therefore, the increased number of grain boundaries raises the recombination rate of photogenerated carriers.

## 4. CONCLUSIONS

We have successfully deposited platinum-doped  $Fe_2O_3$  films on FTO glasses by sol-gel spincoating technique. The crystallite grain sizes are found to vary from 44 nm to 64 nm by XRD analyses. FESEM study showed worm-like morphology with nearly uniform grain distribution. The energy band gaps are found to vary from 1.98 eV to 2.03 eV. The flat band potentials are in the range between -0.135 V and -0.6 V vs. Ag/AgCl electrode. The 0.1 at% Pt-doped sample has the maximum photocurrent density of 0.7 mA/cm<sup>2</sup>.

## References

- 1. M. Momirlana, T.N. Veziroglu, Int. J. Hydrogen Energy 30 (2005) 795.
- 2. C.-L. Tseng, C.-J. Tseng, J.-C. Chen, Int. J. Hydrogen Energy 35 (2010) 2781.
- 3. C.-H. Wang, K.-W. Cheng, C.-J. Tseng, Sol. Energy Mater. Sol. Cells 95 (2011) 453.
- 4. C.-J. Tseng, C.-H. Wang, K.-W. Cheng, Sol. Energy Mater. Sol. Cells 96 (2012) 33.
- 5. Z. Zhang, M.F. Hossain, T. Takahashi, Int. J. Hydrogen Energy 35 (2010) 8528.
- 6. C.-J. Tseng, C.-L. Tseng, Int. J. Hydrogen Energy 36 (2011) 6510.
- 7. A. Fujishima, K. Honda, *Nature* 238 (1972) 37.
- 8. Z. Zhang, P. Wang, Energy Environ. Sci. 5 (2012) 6506.
- 9. J.H. Kennedy, K.W. Frese Jr, J. Electrochem. Soc. 125 (1978) 709.
- 10. V.M. Aroutiounian, V.M. Arakelyan, G.E. Shahnazaryan, H.R. Hovhannisyan, H. Wang, J.A. Turner, *Solar Energy* 81 (2007) 1369.
- 11. V.M. Aroutiounian, V.M. Arakelyan, G.E. Shahnazaryan, G.M. Stepanyan, J.A. Turner, O. Khaselev, *Int. J. Hydrogen Energy* 27 (2002) 33.
- 12. http://rredc.nrel.gov/solar/spectra/am1.5/.
- 13. V.R. Satsangi, S. Kumari, A.P. Singh, R. Shrivastav, S. Dass, *Int. J. Hydrogen Energy* 33 (2008) 312.
- 14. L.S. Flavio, P.L. Kirian, A.P. Nascente, R.L. Edson, Sol. Energy Mater. Sol. Cells 93 (2009) 362.
- 15. W. Luo, T. Yu, Y. Wang, Z. Li, J. Ye, Z. Zou, J. Phys. D: Appl. Phys. 40 (2007) 1091.
- 16. Y. Wang, T. Yu, X. Chen, H. Zhang, S. Ouyang, Z. Li, J. Ye, Z. Zou, *J. Phys. D: Appl. Phys.* 40 (2007) 3925.
- 17. C.J. Sartoretti, B.D. Alexander, R. Solarska, I.A. Rutkowska, J. Augustynski, *J. Phys. Chem. B* 109 (2005) 13685.
- 18. J.C. Manifacier, M.D. Murcia, J.P. Fillard, E. Vicario, Thin Solid Films 41 (1977) 127.
- 19. M.S. Selim, A. Sawaby, Z.S.E. Mandoud, Mater. Res. Bull. 35 (2000) 2123.
- 20. S. Kumari, C. Tripathi, A. P. Singh, D. Chauhan, R. Shrivastav, S. Dass, V.R. Satsangi, *Curr. Sci.* 91 (2006) 1062.
- 21. S. Gota, E. Guiot, M. Henriot, G.S. Martine, Phys. Rev. B 60 (1999) 14387.
- 22. R. A. Ismail, Y. Najim, M. Ouda, J. Surf. Sci. Nanotech. 6 (2008) 96.

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